

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10565863	TAKAISHI, YOSHITOMO
	Examiner	Art Unit
	JOHN W LEE	2624

SEARCHED

Class	Subclass	Date	Examiner
382	132	6/3/2009	John W. Lee
382	168	6/10/2010	John W. Lee

SEARCH NOTES

Search Notes	Date	Examiner
Inventor Search	6/3/2009	John W. Lee
EAST Search	6/3/2009	John W. Lee
IEEE Search	6/3/2009	John W. Lee
EAST Search	11/20/2009	John W. Lee
Plus Search	6/9/2010	John W. Lee
Inventor Search (using EDAN)	6/9/2010	John W. Lee
Inventor Search (using EAST)	6/9/2010	John W. Lee
382/128 and 382/132 (combined with keyword)	6/9/2010	John W. Lee
EAST Search	6/9/2010	John W. Lee
Science direct.com Search	6/10/2010	John W. Lee
IEEE Search	6/10/2010	John W. Lee

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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